

Press Release

For Immediate Release

Test System Conducts Simultaneous Interconnect Tests on the Same Addresses While Actuating Components

Kansas City, MO (July, 1997)—DIT-MCO International Corporation, an international test equipment supplier, announced a breakthrough in a true implementation of “point level” random access in testing wired assemblies with components. The 2500.MBA (Multiple Bus Architecture), patent pending, allows each switching point to simultaneously perform interconnect test while routing power or other instruments to verify complex circuits in wired assemblies. It thoroughly tests interconnects in panels and other subassemblies containing *relays, switches, lights, LEDs, circuit breakers, solenoids, diodes, etc.*, which require actuating the components via external power sources. This test approach helps ensure the integrity and reliability of wired assemblies that must perform to specifications and can not fail in the field.

The 2500.MBA is invaluable to panel shops since it can use both power supplies and instrumentation when testing. A manufacturing engineer that now uses the 2500.MBA cited, “I can’t imagine any panel shop not using the 2500.MBA if they need to apply power to their product.”

About the 2500.MBA

The 2500.MBA conducts accurate, precise continuity and insulation tests, including leakage, resistance, voltage measurements, capacitance, as well as dielectric breakdown and strength. This PC-based test system automates the testing process providing greater fault coverage, faster throughput, while reducing human errors.

2500.MBA’s Key Features

With most test solutions, design revisions require generating paperwork to rework the adapter cables; re-working the cables – tearing open the braiding around the cable and adding splicing to get power to the pins – or building new ones; even producing visual aids for the rework.” Implementing engineering

change orders can take one to two weeks. DIT-MCO's 2500.MBA just requires some changes in the software program and its ready to test the modified assembly.

Other benefits of "true" random access:

- Eliminates the need, costs and maintenance for special, dedicated interfacing such as "Y" adapter cables, internal jumpers, or patch panels.
- Complete point-to-point interconnect testing of wired assemblies containing active components by allowing each switching point to simultaneously perform tests and deliver high voltage or other stimulus to activate a component. (Patent pending)
- One tester outputs one error log for electrical and functional tests. Error reports can contain not only point-to-point information but also intermediate wiring information.

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